

SQFlash Micro SD Card Technical Manual

Class 10 (SQF-MSDx1-xG-21x)

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Revision History

Rev.	Date	History
0.1	2014/8/4	1. 1 st draft
0.2	2014/8/21	1. Add Ultra MLC
0.3	2016/05/18	1. Add TBW table
0.4	2019/3/24	1. Add temperature information
0.5	2020/2/15	1. Add power consumption

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1. Overview

The SQFlash Micro Secure Digital card (SQF-MSD) is fully compliant to the specification released by SD Card Association. The Command List supports [Part 1 Physical Layer Specification Ver3.01 Final] definitions. Card Capacity of Non-secure Area, Secure Area Supports [Part 3 Security Specification Ver3.00 Final] specifications.

The microSD 3.0 card comes with 8-pin interface, designed to operate at a maximum operating frequency of 50MHz or 100MHz. It can alternate communication protocol between the SD mode and SPI mode. It performs data error detection and correction with very low power consumption. Its capacity could be more than 4GB and up to 64GB.

SQFlash Industrial Micro SD card is one of the most popular cards today based on its high performance, good reliability and wide compatibility. Not to mention that it's well adapted for hand-held applications in semi-industrial/medical markets already.

2. Standard Features

- **Support SD system specification version 3.0**
- **Card capacity of non-secure area and secure area support [Part 3 Security Specification Ver3.0 Final] Specifications**
- **Support SD SPI mode**
- **Designed for read-only and read/write cards**
- **Bus Speed Mode (using 4 parallel data lines)**
 - UHS-I mode
 - SDR12 - SDR up to 25MHz 1.8V signaling
 - SDR25 - SDR up to 50MHz 1.8V signaling
 - SDR50: 1.8V signaling, Frequency up to 100 MHz, up to 50MB/sec
 - SDR104: 1.8V signaling, Frequency up to 208MHz, up to 104MB/sec
 - DDR50: 1.8V signaling, Frequency up to 50 MHz, sampled on both clock edges, up to 50MB/sec
 - Note:** Timing in 1.8V signaling is different from that of 3.3V signaling.
- **The command list supports [Part 1 Physical Layer Specification Ver3.1 Final] definitions**
- **Copyrights Protection Mechanism**
 - Compliant with the highest security of SDMI standard
- **Support CPRM (Content Protection for Recordable Media) of SD Card**
- **Card removal during read operation will never harm the content**
- **Password Protection of cards (optional)**
- **Write Protect feature using mechanical switch**
- **Built-in write protection features (permanent and temporary)**
- **+4KV/-4KV ESD protection in contact pads**
- **Operation voltage range: 2.7 ~ 3.6V**

3. Additional Features

■ Capacities

- MLC type : 4GB , 8GB , 16GB , 32GB , 64GB
- Ultra MLC type : 2GB , 4GB , 8GB , 16GB , 32GB

■ Flash type

- A19 nm MLC

■ Performance

Capacity	Mode	Sequential	
		Read (MB/s)	Write (MB/s)
2GB	UHS-I	90	20
4GB	UHS-I	90	20
8GB	UHS-I	90	30
16GB	UHS-I	90	40
32GB	UHS-I	90	40
64GB	UHS-I	90	45

■ Temperature Ranges

- Commercial Temperature
 - -25°C to 85°C for operating
 - -40°C to 85°C for storage
- Industrial Temperature
 - -40°C to 85°C for operating
 - -40°C to 85°C for storage

■ Mechanical Specification

- Shock : 1,500G, Peak / 0.5ms
- Vibration : 20G, Peak / 20~2000Hz
- Drop: 1.5m free fall
- Bending: ≥ 10N, hold 1min / 5times
- Torque: 0.15N-m or +/-2.5deg
- Salt Spray:
 - Concentration: 3% NaCl
 - Temperature: 35°C
 - Storage for 24 HRS
- Waterproof: JIS IPX7 compliance

■ Humidity

- Operating Humidity : 5% ~ 93%
- Non-Operating Humidity : 5% ~ 93%

■ NAND flash Data Retention

- 10 years

■ Endurance

JEDEC defined an endurance rating TBW (TeraByte Written), following by the equation below, for indicating the number of terabytes a flash drive can be written which is a measurement of flash drive's expected lifespan, represents the amount of data written to the device.

$$TBW = [(NAND\ Endurance) \times (Flash\ Drive\ Capacity)] / WAF$$

- **NAND Endurance:** Program / Erase cycle of a NAND flash.
 - SLC: 60,000 cycles
 - Ultra MLC: 20,000 cycles
 - MLC: 3,000 cycles
- **Flash Drive Capacity:** Physical capacity in total of a Flash Drive.
- **WAF:** Write Amplification Factor (WAF), as the equation shown below, is a numerical value representing the ratio between the amount of data that a flash drive controller needs to write and the amount of data that the host's flash controller writes. A better WAF, which is near to 1, guarantees better endurance and lower frequency of data written to flash memory.

$$WAF = (Lifetime\ write\ to\ flash) / (Lifetime\ write\ to\ host)$$

The TBW rating for a flash drive shall be derived for and verified under the following workload conditions,

- Sequential Write (copy file into card)
- P/E cycles incurred: erase count after writing – erase count before writing

➤ SQFlash SD Card TBW

capacity	TBW				
	WAF	SLC	WAF	Ultra MLC	MLC
1 GB	1.024414	58	--	--	--
2 GB		117	1.0301339	39	--
4 GB		234		77	11
8 GB		469		155	23
16 GB		937		310	47
32 GB		1874		621	93
64 GB	--	--		1243	186
128 GB	--	--		--	372

4. Flash Management

■ **Error Correction Code (ECC)**

Flash memory cells will deteriorate with use, which might generate random bit errors in the stored data. Thus, SQF-MSD applies the BCH ECC algorithm, which can detect and correct errors occur during read process, ensure data been read correctly, as well as protect data from corruption.

■ **Wear Leveling**

NAND Flash devices can only undergo a limited number of program/erase cycles, and in most cases, the flash media are not used evenly. If some area get updated more frequently than others, the lifetime of the device would be reduced significantly. Thus, Wear Leveling technique is applied to extend the lifespan of NAND Flash by evenly distributing write and erase cycles across the media.

SQF-MSD provides advanced Wear Leveling algorithm, which can efficiently spread out the flash usage through the whole flash media area. Moreover, by implementing both dynamic and static Wear Leveling algorithms, the life expectancy of the NAND Flash is greatly improved.

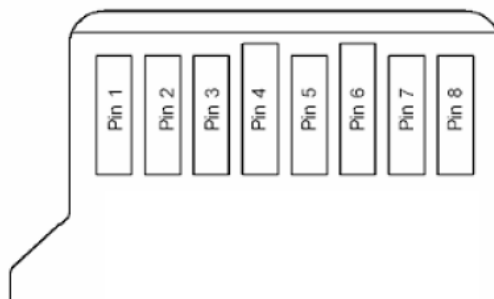
■ **Bad Block Management**

Bad blocks are blocks that include one or more invalid bits, and their reliability is not guaranteed. Blocks that are identified and marked as bad by the manufacturer are referred to as “Initial Bad Blocks”. Bad blocks that are developed during the lifespan of the flash are named “Later Bad Blocks”. SQF-MSD implements an efficient bad block management algorithm to detect the factory-produced bad blocks and manages any bad blocks that appear with use. This practice further prevents data being stored into bad blocks and improves the data reliability.

■ **Auto-Read Refresh**

Auto-Read Refresh is specifically applied on devices that read data mostly but rarely write data, such as GPS. When blocks are continuously read, then the device cannot activate wear leveling since it can only be applied while writing data. Thus, errors will accumulate and become uncorrectable. Accordingly, to avoid errors exceed the amount ECC can correct and blocks turn bad, The firmware of SQF-MSD will automatically refresh the bit errors when the error number in one block approaches the threshold, ex., 24 bits.

5. Pin Assignment and Block Diagram



pin	SD Mode			SPI Mode		
	Name	Type ¹	Description	Name	Type	Description
1	DAT2	I/O/PP	Data Line[bit2]	RSV		
2	CD/DAT3 ²	I/O/PP ³	Card Detect/ Data Line[bit3]	CS	I ³	Chip Select (neg true)
3	CMD	PP	Command/Response	DI	I	Data In
4	V _{DD}	S	Supply voltage	V _{DD}	S	Supply voltage
5	CLK	I	Clock	SCLK	I	Clock
6	V _{SS}	S	Supply voltage ground	V _{SS}	S	Supply voltage ground
7	DAT0	I/O/PP	Data Line[bit0]	DO	O/PP	Data Out
8	DAT1	I/O/PP	Data Line[bit1]	RSV		

- (1) S: power supply, I: input; O: output using push-pull drivers; PP:I/O using push-pull driver
- (2) The extended DAT lines (DAT1-DAT3) are input on power up. They start to operate as DAT lines after SET_BUS_WIDTH command. The Host shall keep its own DAT1-DAT3 lines in input mode, as well, while they are not used. It is defined so, in order to keep compatibility to MultiMedia Cards.
- (3) At power up this line has a 50KOhm pull up enabled in the card. This resistor serves two functions Card detection and Mode Selection. For Mode Selection, the host can drive the line high or let it be pulled high to select SD mode. If the host wants to select SPI mode it should drive the line low. For Card detection, the host detects that the line is pulled high. This pull-up should be disconnected by the user during regular data transfer period, with SET_CLR_CARD_DETECT (ACMD42) command.

Name	Width	Description
CID	128bit	Card identification number; card individual number for identification. Mandatory
RCA ¹	16bit	Relative card address; local system address of a card, dynamically suggested by the card and approved by the host during initialization. Mandatory
DSR	16bit	Driver Stage Register; to configure the card's output drivers. Optional
CSD	128bit	Card Specific Data; information about the card operation conditions. Mandatory
SCR	64bit	SD Configuration Register; information about the SD Memory Card's Special Features capabilities Mandatory
OCR	32bit	Operation conditions register. Mandatory.
SSR	512bit	SD Status; information about the card proprietary features Mandatory
OCR	32bit	Card Status; information about the card status Mandatory

6. Power Consumption

Table list as below is the power consumption of SQF-MSD card with different type of flash memory.
MLC type

(mA)	Read	Write	Idle
4GB	80	80	0.2
8GB	80	80	0.2
16GB	100	100	0.2
32GB	100	100	0.2
64GB	120	130	0.2
128GB	120	180	0.2

UltraMLC type

(mA)	Read	Write	Idle
2GB	80	80	0.2
4GB	80	80	0.2
8GB	100	100	0.2
16GB	100	100	0.2
32GB	120	130	0.2
64GB	120	180	0.2

(1) Data transfer mode is single channel.

7. Electrical Specifications

Absolute Maximum Rating

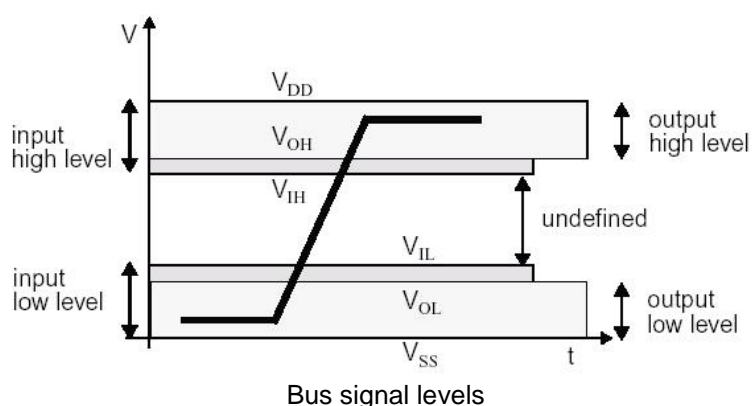
Item	Symbol	Parameter	MIN	MAX	Unit
1	$V_{DD}-V_{SS}$	DC Power Supply	-0.3	+3.3	V
2	V_{IN}	Input Voltage	$V_{SS}-0.3$	$V_{DD}+0.3$	V
3	T_a	Operating Temperature (Gold)	-25	+85	°C
4	T_a	Operating Temperature (Diamond)	-40	+85	°C
5	T_{st}	Storage Temperature	-40	+85	°C
6	V_{DD}	V_{DD} Voltage	2.7	3.6	V

8. DC Characters

■ BUS Operating Conditions for 3.3V Signaling

Threshold level for High Voltage Range

Parameter	Symbol	Min	Max	Unit	Remarks
Supply voltage	VDD	2.7	3.6	V	
Output High Voltage	VOH	0.75*VDD		V	IOH=-100uA VDDMin.
Output Low Voltage	VOL		0.125*VDD	V	IOL = 100uA VDD min
Input High Voltage	VIH	0.625*VDD	VDD+0.3	V	
Input Low Voltage	VIL	VSS-0.3	0.25 *VDD	V	
Power up time			250	ms	from 0v to VDD min.



■ Peak Voltage and Leakage Current

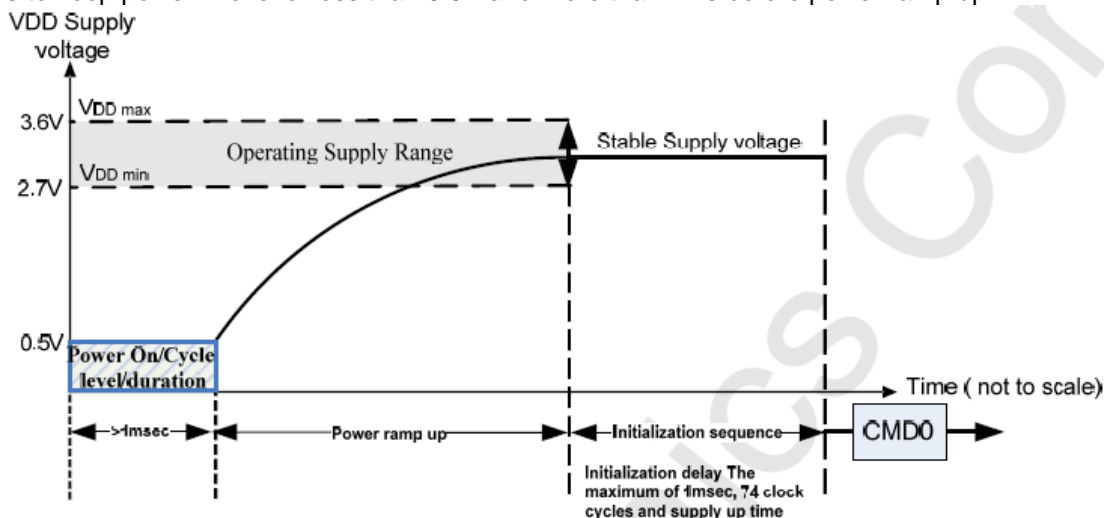
Parameter	Symbol	Min	Max	Unit	Remarks
Peak voltage on all lines		-0.3	V _{DD} +0.3	V	
All Inputs					
Input Leakage Current		-10	10	uA	
All Outputs					
Output Leakage Current		-10	10	uA	

■ Bus Signal Line Levels

Parameter	symbol	Min	Max	Unit	Remark
Pull-up resistance	R _{CMD} R _{DAT}	10	100	kΩ	to prevent bus floating
Total bus capacitance for each signal line	C _L		40	pF	1 card CHOST+CBUS shall not exceed 30 pF
Capacitance of the card for each signal pin	CCAR D		10	pF	
Maximum signal line inductance			16	nH	f _{pp} <20 MHz
Pull-up resistance inside card (pin1)	R _{DAT3}	10	90	kΩ	May be used for card detection

■ Power Up Time

Host needs to keep power line level less than 0.5V and more than 1ms before power ramp up.

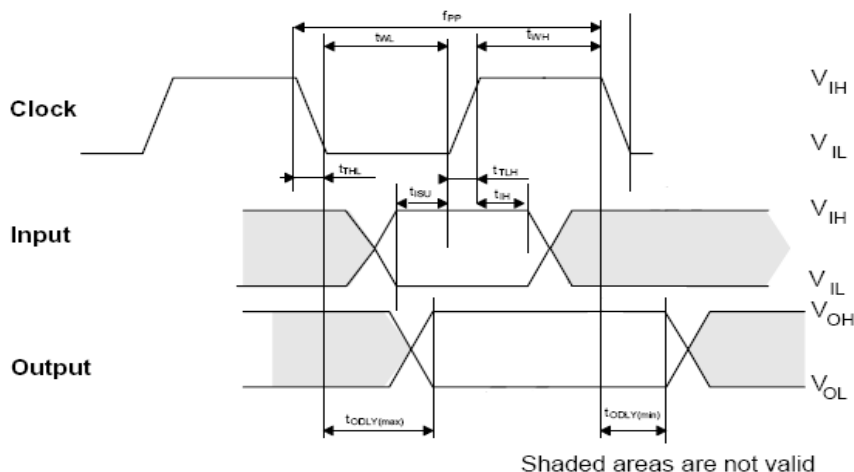


- **Power On or Power Cycle**
Followings are requirements for Power on and Power cycle to assure a reliable SD Card hard reset.
- Voltage level shall be below 0.5V
Duration shall be at least 1ms.
- **Power Supply Ramp Up**
The power ramp up time is defined from 0.5V threshold level up to the operating supply voltage which is stable between VDD (min.) and VDD (max.) and host can supply SDCLK.
- Followings are recommendation of Power ramp up:
Voltage of power ramp up should be monotonic as much as possible.
The minimum ramp up time should be 0.1ms.
The maximum ramp up time should be 35ms for 2.7-3.6V power supply.
- **Power Down and Power Cycle**
When the host shuts down the power, the card VDD shall be lowered to less than 0.5Volt for a minimum period of 1ms. During power down, DAT, CMD, and CLK should be disconnected or driven to logical 0 by the host to avoid a situation that the operating current is drawn through the signal lines.

If the host needs to change the operating voltage, a power cycle is required. Power cycle means the power is turned off and supplied again. Power cycle is also needed for accessing cards that are already in Inactive State. To create a power cycle the host shall follow the power down description before power up the card (i.e. the card VDD shall be once lowered to less than 0.5Volt for a minimum period of 1ms).

9. AC Characters

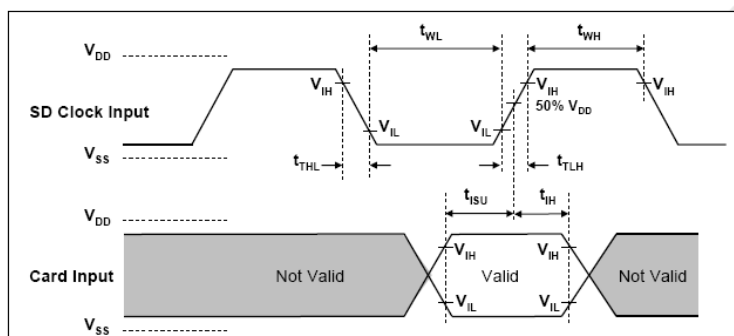
■ microSD Interface timing (Default)



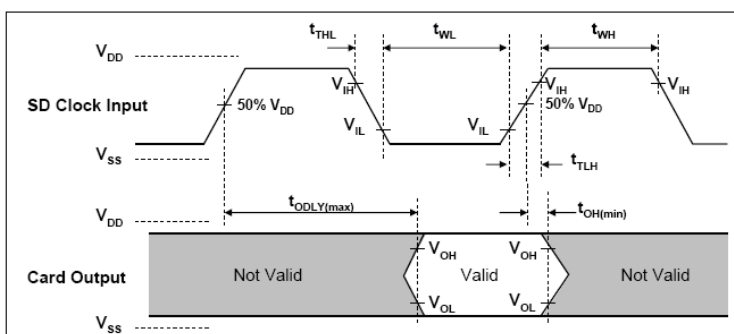
Parameter	Symbol	Min	Max	Unit	Remark
Clock CLK (All values are referred to min(V_{IH}) and max(V_{IL}))					
Clock frequency Data Transfer Mode	f _{PP}	0	25	MHz	C _{card} ≤ 10 pF (1 card)
Clock frequency Identification Mode	f _{OD}	0 ₍₁₎ /100	400	kHz	C _{card} ≤ 10 pF (1 card)
Clock low time	t _{WL}	10		ns	C _{card} ≤ 10 pF (1 card)
Clock high time	t _{WH}	10		ns	C _{card} ≤ 10 pF (1 card)
Clock rise time	t _{TLH}		10	ns	C _{card} ≤ 10 pF (1 card)
Clock fall time	t _{THL}		10	ns	C _{card} ≤ 10 pF (1 card)
Inputs CMD, DAT (referenced to CLK)					
Input set-up time	t _{ISU}	5		ns	C _{card} ≤ 10 pF (1 card)
Input hold time	t _{IH}	5		ns	C _{card} ≤ 10 pF (1 card)
Outputs CMD, DAT (referenced to CLK)					
Output Delay time during Data Transfer Mode	t _{ODLY}	0	14	ns	C _L ≤ 40 pF (1 card)
Output Delay time during Identification Mode	t _{ODLY}	0	50	ns	C _L ≤ 40 pF (1 card)

(1) 0Hz means to stop the clock. The given minimum frequency range is for cases where continuous clock is required.

■ microSD Interface Timing (High-Speed Mode)



Card Input Timing (High Speed Card)



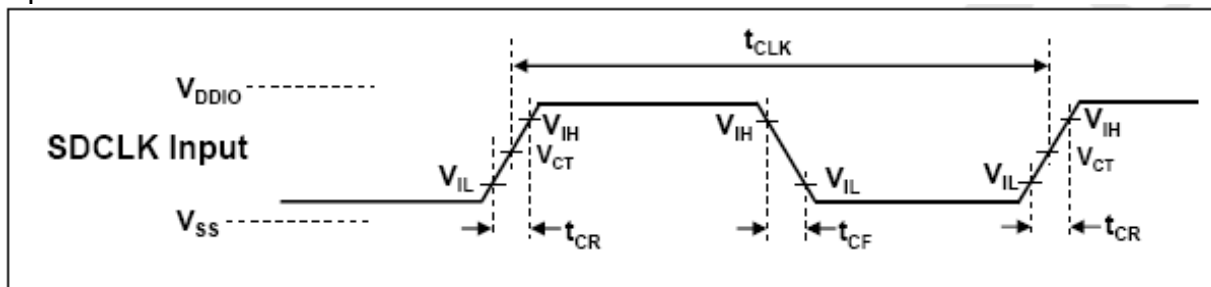
Card Output Timing (High Speed Mode)

Parameter	Symbol	Min	Max	Unit	Remark
Clock CLK (All values are referred to min(V_{IH}) and max(V_{IL}))					
Clock frequency Data Transfer Mode	f _{PP}	0	50	MHz	C _{card} ≤ 10 pF (1 card)
Clock low time	t _{WL}	7		ns	C _{card} ≤ 10 pF (1 card)
Clock high time	t _{WH}	7		ns	C _{card} ≤ 10 pF (1 card)
Clock rise time	t _{TLH}		3	ns	C _{card} ≤ 10 pF (1 card)
Clock fall time	t _{THL}		3	ns	C _{card} ≤ 10 pF (1 card)
Inputs CMD, DAT (referenced to CLK)					
Input set-up time	t _{ISU}	6		ns	C _{card} ≤ 10 pF (1 card)
Input hold time	t _{IH}	2		ns	C _{card} ≤ 10 pF (1 card)
Outputs CMD, DAT (referenced to CLK)					
Output Delay time during Data Transfer Mode	t _{ODLY}		14	ns	C _L ≤ 40 pF (1 card)
Output Hold time	T _{OH}	2.5		ns	C _L ≤ 15 pF (1 card)
Total System capacitance of each line ¹	C _L		40	pF	C _L ≤ 15 pF (1 card)

(1) In order to satisfy severe timing, host shall drive only one card.

■ microSD Interface timing (SDR12, SDR25, SDR50 and SDR104 Modes)

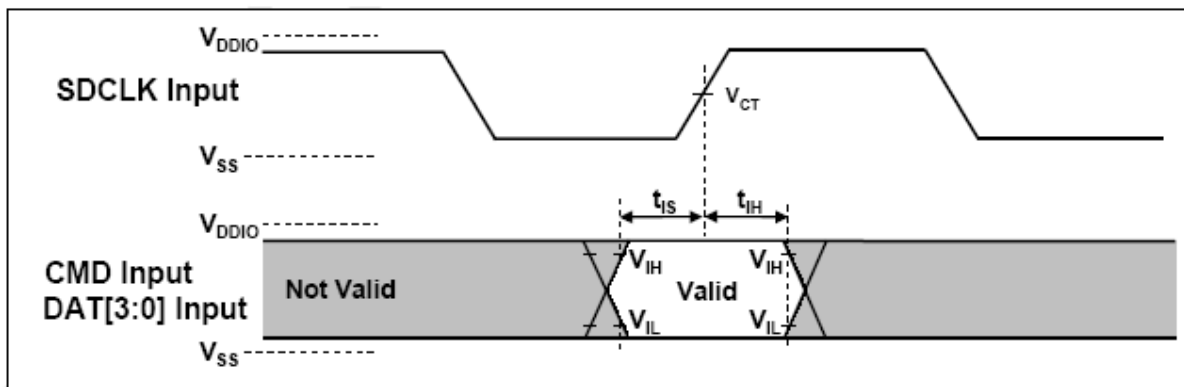
Input



Symbol	Min	Max	Unit	Remark
t _{CLK}	4.80	0	ns	208MHz (Max.), Between rising edge, V _{CT} = 0.975V
t _{CR} , t _{CF}	-	0.2 * t _{CLK}	ns	t _{CR} , t _{CF} < 2.00ns (max.) at 100MHz, C _{CARD} =10pF
Clock Duty	30	70	%	

Clock Signal Timing

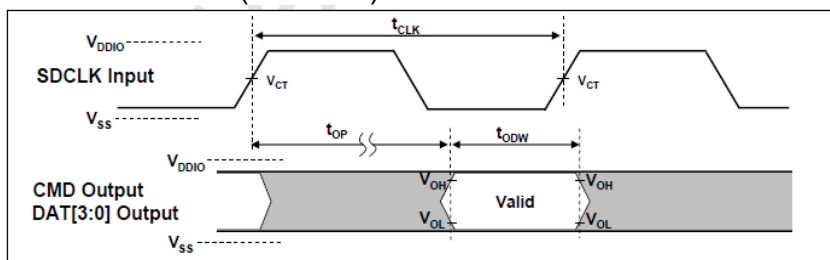
SDR50 and SDR104 Input Timing



Symbol	Min	Max	Unit	SDR104 Mode
t _{IS}	1.40	-	ns	C _{CARD} =10pF, V _{CT} = 0.975V
t _{IH}	0.80	-	ns	C _{CARD} =5pF, V _{CT} = 0.975V
Symbol	Min	Max	Unit	SDR50 Mode
t _{IS}	3.00	-	ns	C _{CARD} =10pF, V _{CT} = 0.975V
t _{IH}	0.80	-	ns	C _{CARD} =5pF, V _{CT} = 0.975V

Card Input Timing

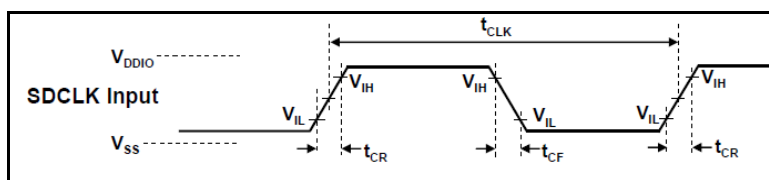
Output Timing of Variable Window (SDR104)



Symbol	Min	Max	Unit	Remark
t _{OP}	0	2	UI	Card Output Phase
Δt _{OP}	-350	+1550	ps	Delay variable due to temperature change after tuning
t _{ODW}	0.60	-	UI	t _{ODW} =2.88ns at 208MHz

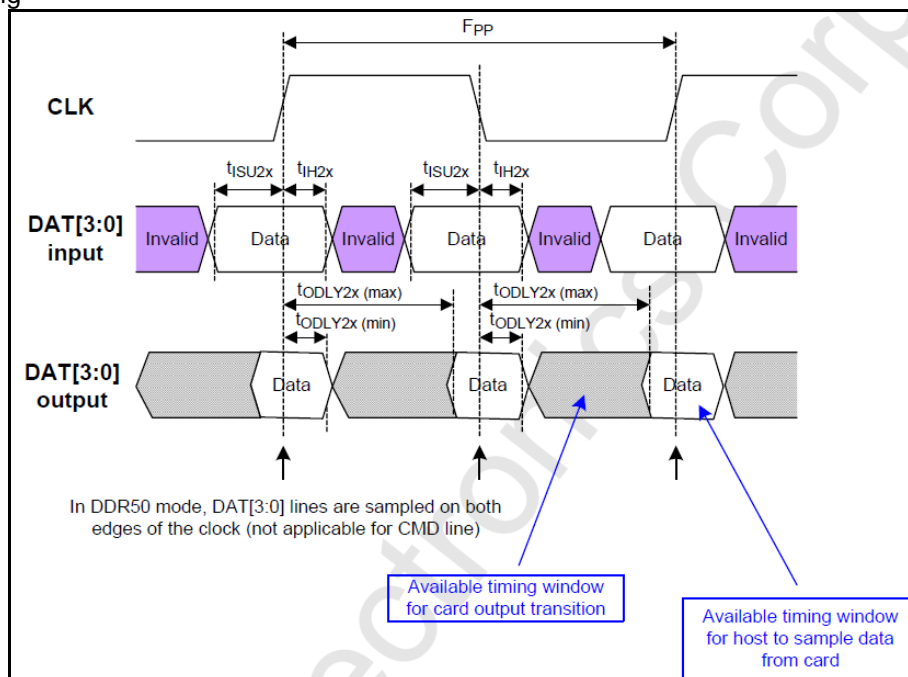
Output Timing of Fixed Data Window

SD Interface timing (DDR50 Modes)



Symbol	Min	Max	Unit	Remark
t _{CLK}	20	-	ns	50MHz (Max.), Between rising edge
t _{CR} , t _{CF}	-	0.2 * t _{CLK}	ns	t _{CR} , t _{CF} < 4.00ns (max.) at 50MHz, CCARD=10pF
Clock Duty	45	55	%	

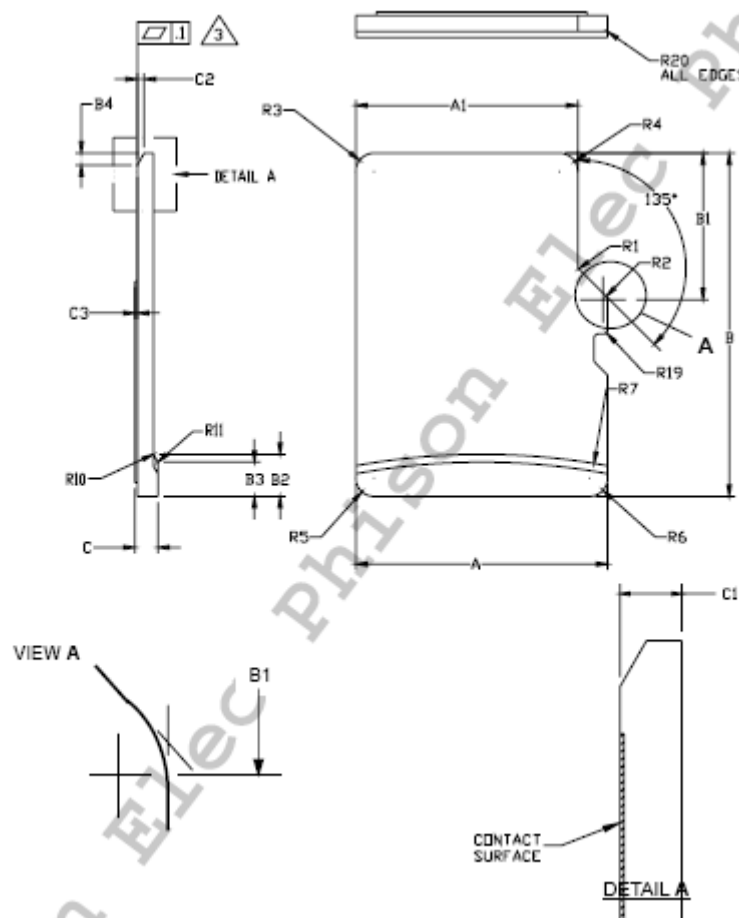
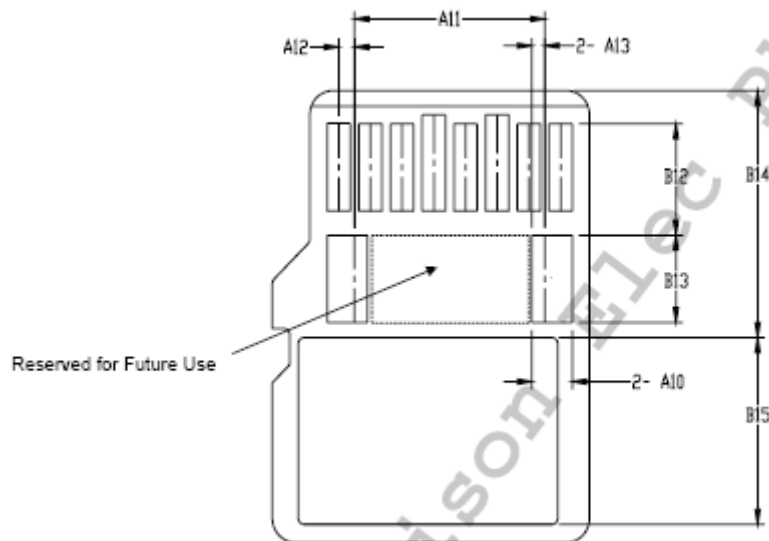
Clock Signal Timing



Timing Diagram DAT Inputs / Outputs Referenced to CLK in DDR50 Mode

Parameter	Symbol	Min	Max	Unit	Remark
Input CMD (referenced to CLK rising edge)					
Input set-up time	t_{ISU}	6	-	ns	$C_{card} \leq 10 \text{ pF}$ (1 card)
Input hold time	t_{IH}	0.8	-	ns	$C_{card} \leq 10 \text{ pF}$ (1 card)
Output CMD (referenced to CLK rising edge)					
Output Delay time during Data Transfer Mode	t_{ODLY}		13.7	ns	$C_{card} \leq 30 \text{ pF}$ (1 card)
Output Hold time	t_{OH}	1.5	-	ns	$C_{card} \leq 10 \text{ pF}$ (1 card)
Inputs DAT (referenced to CLK rising and falling edges)					
Input set-up time	t_{ISU2X}	3	-	ns	$C_{card} \leq 10 \text{ pF}$ (1 card)
Input hold time	t_{IH2X}	0.8	-	ns	$C_{card} \leq 10 \text{ pF}$ (1 card)
Outputs CMD, DAT (referenced to CLK)					
Output Delay time during Data Transfer Mode	t_{ODLY2X}	-	7.0	ns	$C_L \leq 25 \text{ pF}$ (1 card)
Output Hold time	t_{OH2X}	1.5	-	ns	$C_L \geq 15 \text{ pF}$ (1 card)

10. Dimensions



SYMBOL	COMMON DIMENSIONS			NOTE
	MIN	NOM	MAX	
A	10.90	11.00	11.10	
A1	9.60	9.70	9.80	
A2	-	3.85	-	BASIC
A3	7.60	7.70	7.80	
A4	-	1.10	-	BASIC
A5	0.75	0.80	0.85	
A6	-	-	8.50	
A7	0.90	-	-	
A8	0.60	0.70	0.80	
A9	0.80	-	-	
A10	1.35	1.40	1.45	
A11	6.50	6.60	6.70	
A12	0.50	0.55	0.60	
A13	0.40	0.45	0.50	
B	14.90	15.00	15.10	
B1	6.30	6.40	6.50	
B2	1.64	1.84	2.04	
B3	1.30	1.50	1.70	
B4	0.42	0.52	0.62	
B5	2.80	2.90	3.00	
B6	5.50	-	-	
B7	0.20	0.30	0.40	
B8	1.00	1.10	1.20	
B9	-	-	9.00	
B10	7.80	7.90	8.00	
B11	1.10	1.20	1.30	
B12	3.60	3.70	3.80	
B13	2.80	2.90	3.00	
B14	8.20	-	-	
B15	-	-	6.20	
C	0.90	1.00	1.10	
C1	0.60	0.70	0.80	
C2	0.20	0.30	0.40	
C3	0.00	-	0.15	
D1	1.00	-	-	
D2	1.00	-	-	
D3	1.00	-	-	
R1	0.20	0.40	0.60	
R2	0.20	0.40	0.60	
R3	0.70	0.80	0.90	
R4	0.70	0.80	0.90	
R5	0.70	0.80	0.90	
R6	0.70	0.80	0.90	
R7	29.50	30.00	30.50	
R10	-	0.20	-	
R11	-	0.20	-	
R17	0.10	0.20	0.30	
R18	0.20	0.40	0.60	
R19	0.05	-	0.20	
R20	0.02	-	0.15	

Notes:

1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

2. DIMENSIONS ARE IN MILLIMETERS.

3. COPLANARITY IS ADDITIVE TO C1 MAX THICKNESS.

Appendix: Part Number Table

MLC

Product	Advantech PN
SQF MICRO SD C10 MLC 4G (-25~85°C)	SQF-MSDM1-4G-21C
SQF MICRO SD C10 MLC 8G (-25~85°C)	SQF-MSDM1-8G-21C
SQF MICRO SD C10 MLC 16G (-25~85°C)	SQF-MSDM1-16G-21C
SQF MICRO SD C10 MLC 32G (-25~85°C)	SQF-MSDM1-32G-21C
SQF MICRO SD C10 MLC 64G (-25~85°C)	SQF-MSDM1-64G-21C
SQF MICRO SD C10 MLC 128G (-25~85°C)	SQF-MSDM1-128G-21C
SQF MICRO SD C10 MLC 4G (-40~85°C)	SQF-MSDM1-4G-21E
SQF MICRO SD C10 MLC 8G (-40~85°C)	SQF-MSDM1-8G-21E
SQF MICRO SD C10 MLC 16G (-40~85°C)	SQF-MSDM1-16G-21E
SQF MICRO SD C10 MLC 32G (-40~85°C)	SQF-MSDM1-32G-21E
SQF MICRO SD C10 MLC 64G (-40~85°C)	SQF-MSDM1-64G-21E
SQF MICRO SD C10 MLC 128G (-40~85°C)	SQF-MSDM1-128G-21E

Ultra MLC

Product	Advantech PN
SQF MICRO SD C10 UMLC 2G (-25~85°C)	SQF-MSDU1-2G-21C
SQF MICRO SD C10 UMLC 4G (-25~85°C)	SQF-MSDU1-4G-21C
SQF MICRO SD C10 UMLC 8G (-25~85°C)	SQF-MSDU1-8G-21C
SQF MICRO SD C10 UMLC 16G (-25~85°C)	SQF-MSDU1-16G-21C
SQF MICRO SD C10 UMLC 32G (-25~85°C)	SQF-MSDU1-32G-21C
SQF MICRO SD C10 UMLC 2G (-40~85°C)	SQF-MSDU1-2G-21E
SQF MICRO SD C10 UMLC 4G (-40~85°C)	SQF-MSDU1-4G-21E
SQF MICRO SD C10 UMLC 8G (-40~85°C)	SQF-MSDU1-8G-21E
SQF MICRO SD C10 UMLC 16G (-40~85°C)	SQF-MSDU1-16G-21E
SQF MICRO SD C10 UMLC 32G (-40~85°C)	SQF-MSDU1-32G-21E